TOSHIBA 2SC2500

TOSHIBA TRANSISTOR SILICON NPN EPITAXIAL TYPE (PCT PROCESS)

2 S C 2 5 0 0

STROBE FLASH APPLICATIONS.

MEDIUM POWER AMPLIFIER APPLICATIONS.

High DC Current Gain and Excellent hFE Linearity

: $h_{FE (1)} = 140 \sim 600 \text{ (V}_{CE} = 1\text{V, I}_{C} = 0.5\text{A})$: $h_{FE (2)} = 70 \text{ (Min.)}, 200 \text{ (Typ.)} \text{ (V}_{CE} = 1\text{V, I}_{C} = 2\text{A})$

Low Saturation Voltage

: $V_{CE (sat)} = 0.5V (Max.) (I_{C} = 2A, I_{B} = 50mA)$

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	RATING	UNIT	
Collector-Base Voltage		V _{CBO}	30	V	
Collector-Emitter Voltage		v_{CES}	30	v	
		v_{CEO}	10		
Emitter-Base Voltage		v_{EBO}	6	V	
Collector Current	DC	$I_{\mathbf{C}}$	2	A	
	Pulsed (Note 1)	I _{CP}	5		
Base Current		$I_{\mathbf{B}}$	0.5	Α	
Collector Power Dissipation		P_{C}	P _C 900		
Junction Temperature		T_{j}	150	°C	
Storage Temperature Range		$\mathrm{T_{stg}}$	-55~150	°C	

5.1MAX 0.75MAX 1.0MAX 0.6MAX **EMITTER** 2. COLLECTOR 3. BASE JEDEC TO-92MOD

2-5J1A

Unit in mm

Weight: 0.36g

TOSHIBA

EIAJ

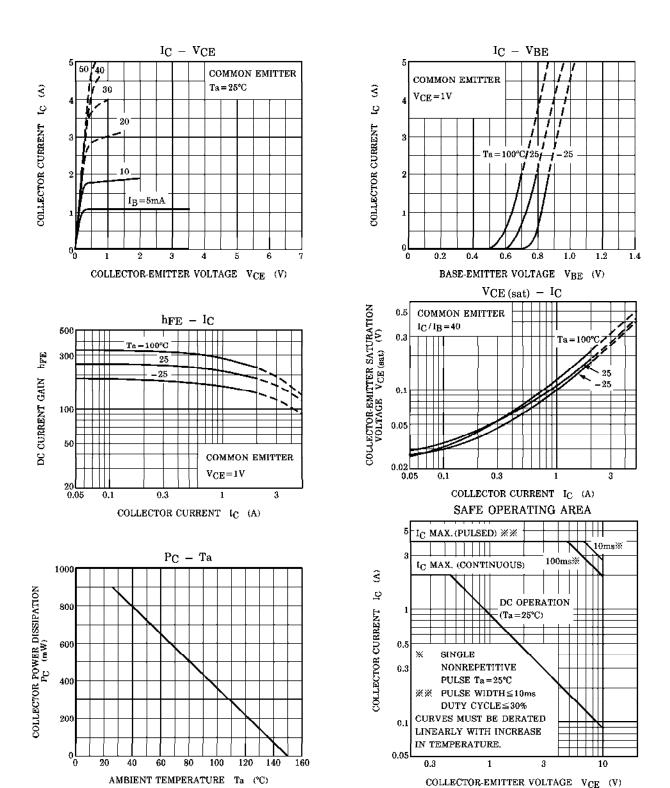
Note 1 : Pulse Width ≤ 10ms, Duty Cycle ≤ 30%

ELECTRICAL CHARACTERISTICS (Ta = 25°C)

ELECTRICAL CHARACTERISTICS (TO						
CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Current	ICBO	$V_{CB}=30V$, $I_{E}=0$	_	_	100	nA
Emitter Cut-off Current	IEBO	$V_{EB}=6V$, $I_{C}=0$	_	_	100	nА
Collector-Emitter Breakdown Voltage	VCEO	$I_C = 10$ mA, $I_B = 0$	10	_	_	v
Emitter-Base Breakdown Voltage	$v_{\rm EBO}$	I _E =1mA, I _C =0	6	_	_	v
DC Current Gain	hFE (1) (Note 2)	$V_{CE} = 1V, I_{C} = 0.5A$	140	_	600	
	hFE (2)	$V_{CE} = 1V$, $I_{C} = 2A$	70	200	—	
Collector-Emitter Saturation Voltage	V _{CE} (sat)	I _C =2A, I _B =50mA	_	0.2	0.5	V
Base-Emitter Voltage	$V_{\mathbf{BE}}$	$V_{CE} = 1V, I_{C} = 2A$	_	0.86	1.5	V
Transition Frequency	$ m f_{T}$	$V_{\rm CE} = 1V, I_{\rm C} = 0.5A$	_	150	_	MHz
Collector Output Capacitance	Cob	$V_{CB} = 10V, I_E = 0, f = 1MHz$		27	_	рF

Note 2: hFE(1) Classification A: 140~240, B: 200~330, C: 300~450, D: 420~600

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